

<b>Notice of References Cited</b>	Application/Control No. 10/657,122	Applicant(s)/Patent Under Reexamination WANG, HANK	
	Examiner Seung H. Lee	Art Unit 2876	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,166,324	12-2000	Oldendorf et al.	174/35R
	B	US-6,051,781	04-2000	Bianca et al.	174/35C
	C	US-RE36,540	02-2000	Farquhar et al.	156/73.1
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
✓	N	EP 350179 A1	01-1990	European Patent	JARVIS, CHARLES RICHARD	B29C 67/24
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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